











SN74LVC2G74

SCES203O - APRIL 1999 - REVISED JANUARY 2015

# SN74LVC2G74 Single Positive-Edge-Triggered D-Type Flip-Flop With Clear and Preset

#### **Features**

- Available in the Texas Instruments NanoFree™ Package
- Supports 5-V V<sub>CC</sub> Operation
- Inputs Accept Voltages to 5.5 V
- Max  $t_{pd}$  of 5.9 ns at 3.3 V
- Low Power Consumption, 10-µA Max I<sub>CC</sub>
- ±24-mA Output Drive at 3.3 V
- Typical V<sub>OLP</sub> (Output Ground Bounce)  $< 0.8 \text{ V at V}_{CC} = 3.3 \text{ V}, T_A = 25^{\circ}\text{C}$
- Typical V<sub>OHV</sub> (Output V<sub>OH</sub> Undershoot)  $> 2 \text{ V at V}_{CC} = 3.3 \text{ V}, T_A = 25^{\circ}\text{C}$
- I<sub>off</sub> Supports Live Insertion, Partial-Power-Down Mode, and Back-Drive Protection
- Latch-Up Performance Exceeds 100 mA Per JESD 78, Class II
- ESD Protection Exceeds JESD 22
  - 2000-V Human-Body Model
  - 200-V Machine Model
  - 1000-V Charged-Device Model

## **Applications**

- Servers
- LED displays
- Network switch
- Telecom infrastructure
- Motor drivers
- I/O Expanders

# Simplified Schematic

#### 3 Description

This single positive-edge-triggered D-type flip-flop is designed for 1.65-V to 5.5-V V<sub>CC</sub> operation.

NanoFree™ package technology is a major breakthrough in IC packaging concepts, using the die as the package.

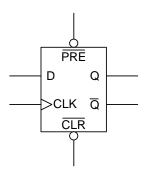
A low level at the preset (PRE) or clear (CLR) input sets or resets the outputs, regardless of the levels of the other inputs. When PRE and CLR are inactive (high), data at the data (D) input meeting the setup time requirements is transferred to the outputs on the positive-going edge of the clock pulse. Clock triggering occurs at a voltage level and is not related directly to the rise time of the clock pulse. Following the hold-time interval, data at the D input can be changed without affecting the levels at the outputs.

This device is fully specified for partial-power-down applications using Ioff. The Ioff circuitry disables the outputs, preventing damaging current backflow through the device when it is powered down.

#### Device Information<sup>(1)</sup>

PART NUMBER	PACKAGE	BODY SIZE		
	SSOP (8)	2.95 mm × 2.80 mm		
SN74LVC2G74	VSSOP (8)	2.30 mm × 2.00 mm		
	DSBGA (8)	1.91 mm × 0.91 mm		

(1) For all available packages, see the orderable addendum at the end of the data sheet.





#### **Table of Contents**

1	Features 1	8	Parameter Measurement Information	8
2	Applications 1	9	Detailed Description	9
3	Description 1		9.1 Overview	
4	Simplified Schematic1		9.2 Functional Block Diagram	9
5	Revision History2		9.3 Feature Description	9
6	Pin Configuration and Functions		9.4 Device Functional Modes	9
7	Specifications4	10	Application and Implementation	10
'	7.1 Absolute Maximum Ratings		10.1 Application Information	10
	7.2 ESD Ratings		10.2 Typical Power Button Circuit	10
	7.3 Recommended Operating Conditions	11	Power Supply Recommendations	11
	7.4 Thermal Information	12	Layout	
	7.5 Electrical Characteristics		12.1 Layout Guidelines	
	7.6 Timing Requirements, –40°C to 85°C		12.2 Layout Example	
	7.7 Timing Requirements, –40°C to 125°C	13	Device and Documentation Support	
	7.8 Switching Characteristics, –40°C to 85°C		13.1 Trademarks	
	7.9 Switching Characteristics, –40°C to 125°C		13.2 Electrostatic Discharge Caution	
	7.10 Operating Characteristics		13.3 Glossary	
	7.11 Typical Characteristics	14	Mechanical, Packaging, and Orderable Information	

## 5 Revision History

#### Changes from Revision N (July 2013) to Revision O

**Page** 

Added Applications, Device Information table, Pin Functions table, ESD Ratings table, Thermal Information table,
Typical Characteristics, Feature Description section, Device Functional Modes, Application and Implementation
section, Power Supply Recommendations section, Layout section, Device and Documentation Support section, and
Mechanical, Packaging, and Orderable Information section.

Changes from Revision M (February 2007) to Revision N

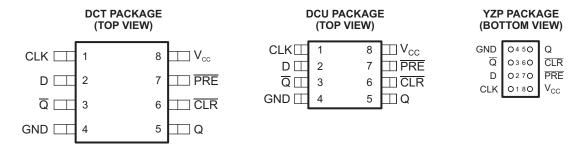
Page

•	Changed I <sub>off</sub> description in Features.	. 1
	Added parameter values for –40 to 125°C temperature ratings in <i>Electrical Characteristics</i> table	
•	Changed Timing Requirements, –40°C to 85°C table	. 6
•	Added Timing Requirements, –40°C to 125°C table	. 6
	Changed Switching Characteristics, –40°C to 85°C table	
	Added Switching Characteristics 40°C to 125°C toble	-

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# 6 Pin Configuration and Functions



See mechanical drawings for dimensions.

#### **Pin Functions**

	PIN		
NAME	NO.	TYPE	DESCRIPTION
CLK	1	I	Clock input
CLR	6	I	Clear input - Pull low to set Q output low
D	2	I	Input
GND	4	_	Ground
Q	5	0	Output
Q	3	0	Inverted output
PRE	7	I	Preset input - Pull low to set Q output high
V <sub>CC</sub>	8	_	Supply



#### 7 Specifications

#### 7.1 Absolute Maximum Ratings

over operating free-air temperature range (unless otherwise noted)<sup>(1)</sup>

			MIN	MAX	UNIT
$V_{CC}$	Supply voltage range		-0.5	6.5	V
$V_{I}$	Input voltage range (2)		-0.5	6.5	V
$V_{O}$	Voltage range applied to any output in the high-	Itage range applied to any output in the high-impedance or power-off state (2)			
Vo	Voltage range applied to any output in the high	-0.5	V <sub>CC</sub> + 0.5	V	
I <sub>IK</sub>	Input clamp current	V <sub>I</sub> < 0		-50	mA
$I_{OK}$	Output clamp current	V <sub>O</sub> < 0		-50	mA
Io	Continuous output current			±50	mA
	Continuous current through V <sub>CC</sub> or GND				mA
T <sub>stg</sub>	Storage temperature range		-65	150	°C

<sup>(1)</sup> Stresses beyond those listed under Absolute Maximum Ratings may cause permanent damage to the device. These are stress ratings only, and functional operation of the device at these or any other conditions beyond those indicated under Recommended Operating Conditions is not implied. Exposure to absolute-maximum-rated conditions for extended periods may affect device reliability.

#### 7.2 ESD Ratings

	PARAMETER	DEFINITION	VALUE	UNIT
		Human body model (HBM), per ANSI/ESDA/JEDEC JS-001, all pins <sup>(1)</sup>	2000	
V <sub>(ESD)</sub>	Electrostatic discharge	Charged device model (CDM), per JEDEC specification JESD22-C101, all pins (2)	1000	V

Product Folder Links: SN74LVC2G74

1) JEDEC document JEP155 states that 500-V HBM allows safe manufacturing with a standard ESD control process.

(2) JEDEC document JEP157 states that 250-V CDM allows safe manufacturing with a standard ESD control process.

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<sup>(2)</sup> The input negative-voltage and output voltage ratings may be exceeded if the input and output clamp-current ratings are observed.

<sup>(3)</sup> The value of V<sub>CC</sub> is provided in the *Recommended Operating Conditions* table.



## 7.3 Recommended Operating Conditions

over operating free-air temperature range (unless otherwise noted)<sup>(1)</sup>

			MIN	MAX	UNIT	
.,	Complexed to the	Operating	1.65	5.5	V	
V <sub>CC</sub>	Supply voltage	Data retention only	1.5		V	
		V <sub>CC</sub> = 1.65 V to 1.95 V	0.65 × V <sub>CC</sub>			
	LPak Level Construction	V <sub>CC</sub> = 2.3 V to 2.7 V	1.7		V	
$V_{IH}$	High-level input voltage	t voltage $V_{CC} = 3 \text{ V to } 3.6 \text{ V}$				
		V <sub>CC</sub> = 4.5 V to 5.5 V	0.7 × V <sub>CC</sub>			
		V <sub>CC</sub> = 1.65 V to 1.95 V		0.35 × V <sub>CC</sub>		
	Level Secret Secretaria	V <sub>CC</sub> = 2.3 V to 2.7 V		0.7	.,	
$V_{IL}$	Low-level input voltage	V <sub>CC</sub> = 3 V to 3.6 V		0.8	V	
		V <sub>CC</sub> = 4.5 V to 5.5 V		0.3 × V <sub>CC</sub>		
VI	Input voltage		0	5.5	V	
Vo	Output voltage		0	V <sub>CC</sub>	V	
-		V <sub>CC</sub> = 1.65 V		-4		
		V <sub>CC</sub> = 2.3 V		-8		
I <sub>OH</sub>	High-level output current	V 0V		-16	mA	
		V <sub>CC</sub> = 3 V		-24		
		V <sub>CC</sub> = 4.5 V		-32		
		V <sub>CC</sub> = 1.65 V		4		
		V <sub>CC</sub> = 2.3 V		8		
$I_{OL}$	Low-level output current	V 2V		16	mA	
		V <sub>CC</sub> = 3 V		24		
		V <sub>CC</sub> = 4.5 V		32		
		$V_{CC} = 1.8 \text{ V} \pm 0.15 \text{ V}, 2.5 \text{ V} \pm 0.2 \text{ V}$		20		
Δt/Δν	Input transition rise or fall rate	$V_{CC} = 3.3 \text{ V} \pm 0.3 \text{ V}$		10	ns/V	
		$V_{CC} = 5 \text{ V} \pm 0.5 \text{ V}$		5		
T <sub>A</sub>	Operating free-air temperature		-40	125	°C	

<sup>(1)</sup> All unused inputs of the device must be held at  $V_{CC}$  or GND to ensure proper device operation. Refer to the TI application report, Implications of Slow or Floating CMOS Inputs, literature number SCBA004.

#### 7.4 Thermal Information

	THERMAL METRIC <sup>(1)</sup>	DCT	YZP	UNIT	
			6 PINS		
$R_{\theta JA}$	Junction-to-ambient thermal resistance <sup>(2)</sup>	220	227	102	°C/W

<sup>(1)</sup> For more information about traditional and new thermal metrics, see the IC Package Thermal Metrics application report, SPRA953.

<sup>(2)</sup> The package thermal impedance is calculated in accordance with JESD 51-7.



#### 7.5 Electrical Characteristics

over recommended operating free-air temperature range (unless otherwise noted)

					-40°C	MIN TYP MAX  V <sub>CC</sub> - 0.1  1.2  1.85  2.4  2.3  3.8  0.1  0.45  0.3  0.4  0.55  0.55			
PARAMETER	TEST CONDITIONS	V <sub>cc</sub>	-40°C	to 85°C	Recon	UNIT			
			MIN	TYP <sup>(1)</sup> MAX	MIN	TYP MAX	V		
	I <sub>OH</sub> = -100 μA	1.65 V to 5.5 V	V <sub>CC</sub> - 0.1		V <sub>CC</sub> - 0.1				
	$I_{OH} = -4 \text{ mA}$	1.65 V	1.2		1.2				
V <sub>ОН</sub>	$I_{OH} = -8 \text{ mA}$	2.3 V	1.9		1.85		.,		
	I <sub>OH</sub> = -16 mA	3 V	2.4		2.4		V		
	$I_{OH} = -24 \text{ mA}$	3 V	2.3		2.3				
	$I_{OH} = -32 \text{ mA}$	4.5 V	3.8		3.8				
	I <sub>OL</sub> = 100 μA	1.65 V to 5.5 V		0.1		0.1			
	I <sub>OL</sub> = 4 mA	1.65 V		0.45		0.45			
N/	I <sub>OL</sub> = 8 mA	2.3 V		0.3		0.3			
V <sub>OL</sub>	I <sub>OL</sub> = 16 mA	3 V		0.4		0.4	V		
	I <sub>OL</sub> = 24 mA	3 V		0.55		0.55			
	I <sub>OL</sub> = 32 mA	4.5 V		0.55		0.55			
I <sub>I</sub> Data or control inputs	V <sub>I</sub> = 5.5 V or GND	0 to 5.5 V		±5		±5	μA		
I <sub>off</sub>	V <sub>I</sub> or V <sub>O</sub> = 5.5 V	0		±10		±10	μA		
I <sub>cc</sub>	$V_I = 5.5 \text{ V or GND}, \qquad I_O = 0$	1.65 V to 5.5 V		10		10	μA		
ΔI <sub>CC</sub>	One input at $V_{CC}$ – 0.6 V, Other inputs at $V_{CC}$ or GND	3 V to 5.5 V		500		500	μA		
Ci	V <sub>I</sub> = V <sub>CC</sub> or GND	3.3 V		5		5	pF		

<sup>(1)</sup> All typical values are at  $V_{CC} = 3.3 \text{ V}$ ,  $T_A = 25^{\circ}\text{C}$ .

## 7.6 Timing Requirements, -40°C to 85°C

over recommended operating free-air temperature range (unless otherwise noted) (see Figure 3)

			−40°C to 85°C								
PARAMETER	FROM	то	V <sub>CC</sub> = 1.1 ± 0.15	8 V V	V <sub>CC</sub> = 2 ± 0.2		V <sub>CC</sub> = 3 ± 0.3		V <sub>CC</sub> = 5 ± 0.5	5 V V	UNIT
			MIN	MAX	MIN	MAX	MIN	MAX	MIN	MAX	
f <sub>clock</sub>	•	•		80		175		175		200	MHz
	C	CLK	6.2		2.7		2.7		2		ns
ı <sub>w</sub>	PRE or	CLR low	6.2		2.7		2.7		2		
		Data	2.9		1.7		1.3		1.1		ns
L <sub>Su</sub>	PRE or C	CLR inactive	1.9		1.4		1.2		1		
t <sub>h</sub>			0		0.3		1.2		0.5		ns

## 7.7 Timing Requirements, -40°C to 125°C

over recommended operating free-air temperature range (unless otherwise noted) (see Figure 3)

					-	-40°C to 1	25°C				
PARAMETER	FROM	то	V <sub>CC</sub> = 1.8 ± 0.15 \		V <sub>CC</sub> = 2 ± 0.2		V <sub>CC</sub> = 3 ± 0.3		V <sub>CC</sub> = 5 ± 0.5		UNIT
			MIN	MAX	MIN	MAX	MIN	MAX	MIN	MAX	
f <sub>clock</sub>		•		80		120		120		140	MHz
	C	CLK	6.2		3.5		3.5		3.3		ns
ı <sub>w</sub>	PRE or	CLR low	6.2		3.5		3.5		3.3		
	D	ata	2.9		23		1.9		1.7		
I <sub>su</sub>	PRE or C	LR inactive	1.9		2		1.8		1.6		ns
t <sub>h</sub>			0		0.3		0.5		0.5		ns



## 7.8 Switching Characteristics, -40°C to 85°C

over recommended operating free-air temperature range (unless otherwise noted) (see Figure 3)

	, ,			−40°C to 85°C							
PARAMETER	FROM	то	V <sub>CC</sub> = 1.8 V V <sub>CC</sub> = 2.5 V V <sub>C</sub> ± 0.15 V ± 0.2 V				.3 V V	V <sub>CC</sub> = 5 V ± 0.5 V		UNIT	
			MIN	MAX	MIN	MAX	MIN	MAX	MIN	MAX	
f <sub>max</sub>			80		175		175		200		MHz
	CLK	Q	4.8	13.4	2.2	7.1	2.2	5.9	1.4	4.1	
t <sub>pd</sub>	CLK	Q	6	14.4	3	7.7	2.6	6.2	1.6	4.4	ns
	PRE or CLR low	Q or Q	4.4	12.9	2.3	7	1.7	5.9	1.6	4.1	

#### 7.9 Switching Characteristics, -40°C to 125°C

over recommended operating free-air temperature range (unless otherwise noted) (see Figure 3)

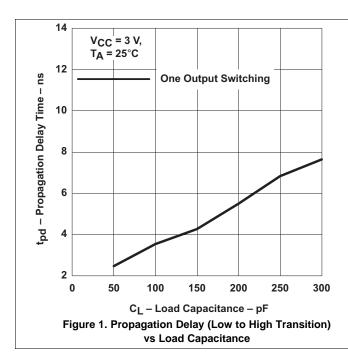
PARAMETER	-40°C to 125°C										
	FROM	то	V <sub>CC</sub> = 1.8 V ± 0.15 V		V <sub>CC</sub> = 2.5 V ± 0.2 V		V <sub>CC</sub> = 3.3 V ± 0.3 V		V <sub>CC</sub> = 5 V ± 0.5 V		UNIT
				MIN	MAX	MIN	MAX	MIN	MAX	MIN	MAX
f <sub>max</sub>			80		120		120		140		MHz
	CLK	Q	4.8	14.4	2.2	8.1	2.2	6.9	1.4	5.1	
t <sub>pd</sub>		Īα	6	16	3	9.7	2.6	7.2	1.6	5.4	ns
	PRE or CLR low	Q or Q	4.4	14.9	2.3	9.5	1.7	7.9	1.6	6.1	

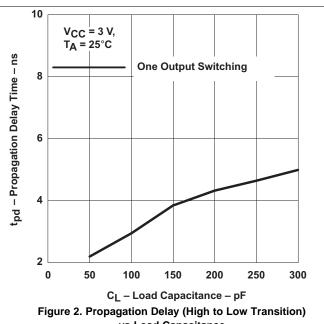
#### 7.10 Operating Characteristics

 $T_A = 25^{\circ}C$ 

	PARAMETER	TEST CONDITIONS	V <sub>CC</sub> = 1.8 V	$V_{CC} = 2.5 \text{ V}$	$V_{CC} = 3.3 \text{ V}$	$V_{CC} = 5 V$	UNIT	
	FARAINETER	TEST CONDITIONS	TYP	TYP	TYP	TYP	UNII	
$C_{pd}$	Power dissipation capacitance	f = 10 MHz	35	35	37	40	pF	

## 7.11 Typical Characteristics

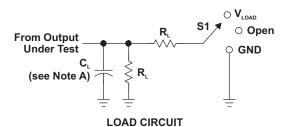




vs Load Capacitance

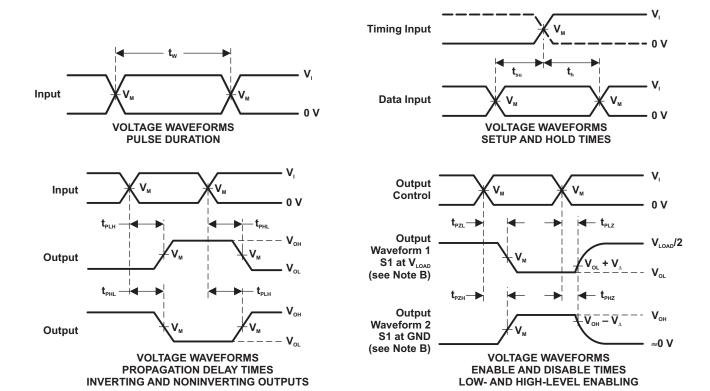


#### 8 Parameter Measurement Information



TEST	S1
t <sub>PLH</sub> /t <sub>PHL</sub>	Open
t <sub>PLZ</sub> /t <sub>PZL</sub>	<b>V</b> <sub>LOAD</sub>
t <sub>PHZ</sub> /t <sub>PZH</sub>	GND

.,	INI	PUTS		V		1	.,
V <sub>cc</sub>	V,	t,/t,	V <sub>M</sub>	<b>V</b> <sub>LOAD</sub>	C <sub>L</sub>	$R_{\scriptscriptstyle L}$	V <sub>A</sub>
1.8 V ± 0.15 V	V <sub>cc</sub>	≤2 ns	V <sub>cc</sub> /2	2 × V <sub>cc</sub>	30 pF	<b>1 k</b> Ω	0.15 V
2.5 V ± 0.2 V	V <sub>cc</sub>	≤2 ns	V <sub>cc</sub> /2	2 × V <sub>cc</sub>	30 pF	500 $\Omega$	0.15 V
3.3 V ± 0.3 V	3 V	≤2.5 ns	1.5 V	6 V	50 pF	500 $\Omega$	0.3 V
5 V ± 0.5 V	V <sub>cc</sub>	≤2.5 ns	V <sub>cc</sub> /2	2 × V <sub>cc</sub>	50 pF	500 $\Omega$	0.3 V



NOTES: A. C<sub>L</sub> includes probe and jig capacitance.

- B. Waveform 1 is for an output with internal conditions such that the output is low, except when disabled by the output control. Waveform 2 is for an output with internal conditions such that the output is high, except when disabled by the output control.
- C. All input pulses are supplied by generators having the following characteristics: PRR  $\leq$  10 MHz,  $Z_{\circ}$  = 50  $\Omega$ .
- D. The outputs are measured one at a time, with one transition per measurement.
- E.  $t_{\mbox{\tiny PLZ}}$  and  $t_{\mbox{\tiny PHZ}}$  are the same as  $t_{\mbox{\tiny dis}}.$
- F.  $t_{PZL}$  and  $t_{PZH}$  are the same as  $t_{en}$ .
- G.  $t_{PLH}$  and  $t_{PHL}$  are the same as  $t_{pd}$ .
- H. All parameters and waveforms are not applicable to all devices.

Figure 3. Load Circuit and Voltage Waveforms

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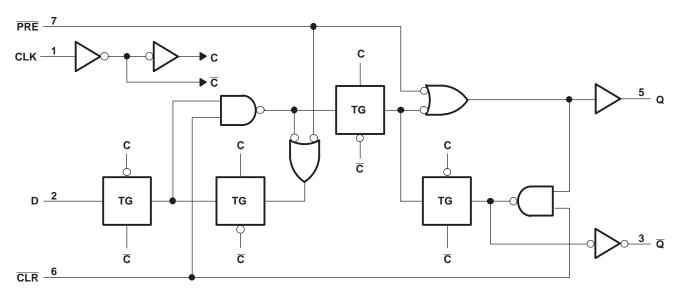


## 9 Detailed Description

#### 9.1 Overview

This device is fully specified for partial-power-down applications using  $I_{off}$ . The  $I_{off}$  circuitry disables the outputs, preventing damaging current backflow through the device when it is powered down.

#### 9.2 Functional Block Diagram



#### 9.3 Feature Description

- Allows down voltage translation
  - 5 V to 3.3 V
  - 5 V or 3.3 V to 1.8V
- Inputs accept voltage levels up to 5.5 V
- I<sub>off</sub> Feature
  - Can prevent backflow current that can damage device when powered down.

#### 9.4 Device Functional Modes

**Table 1. Function Table** 

	INP	OUTPUTS			
PRE	CLR	CLK	D	Q	Q
L	Н	X	X	Н	L
Н	L	X	X	L	Н
L	L	X	X	H <sup>(1)</sup>	H <sup>(1)</sup>
Н	Н	<b>↑</b>	Н	Н	L
Н	Н	<b>↑</b>	L	L	Н
Н	Н	L	X	$Q_0$	$\overline{Q}_0$

(1) This configuration is non-stable; that is, it does not persist when  $\overline{\text{PRE}}$  or  $\overline{\text{CLR}}$  returns to its inactive (high) level.



## 10 Application and Implementation

#### NOTE

Information in the following applications sections is not part of the TI component specification, and TI does not warrant its accuracy or completeness. TI's customers are responsible for determining suitability of components for their purposes. Customers should validate and test their design implementation to confirm system functionality.

#### 10.1 Application Information

A low level at the preset (PRE) or clear (CLR) input sets or resets the outputs, regardless of the levels of the other inputs. When PRE and CLR are inactive (high), data at the data (D) input meeting the setup time requirements is transferred to the outputs on the positive-going edge of the clock pulse. Clock triggering occurs at a voltage level and is not related directly to the rise time of the clock pulse. Following the hold-time interval, data at the D input can be changed without affecting the levels at the outputs.

The resistor and capacitor at the  $\overline{\text{CLR}}$  pin are optional. If they are not used, the  $\overline{\text{CLR}}$  pin should be connected directly to  $V_{CC}$  to be inactive.

#### 10.2 Typical Power Button Circuit

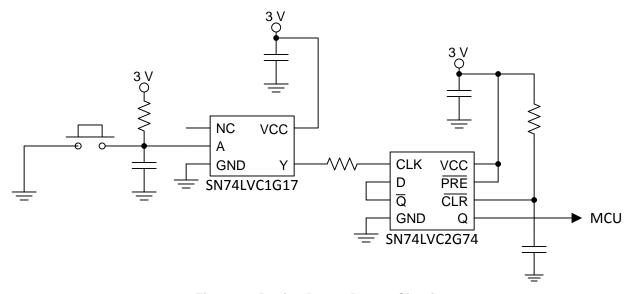


Figure 4. Device Power Button Circuit

#### 10.2.1 Design Requirements

This device uses CMOS technology and has balanced output drive. Care should be taken to avoid bus contention because it can drive currents that would exceed maximum limits. Outputs can be combined to produce higher drive but the high drive will also create faster edges into light loads so routing and load conditions should be considered to prevent ringing.

#### 10.2.2 Detailed Design Procedure

- 1. Recommended Input Conditions:
  - For rise time and fall time specifications, see ( $\Delta t/\Delta V$ ) in *Recommended Operating Conditions* table.
  - For specified high and low levels, see (V<sub>IH</sub> and V<sub>IL</sub>) in Recommended Operating Conditions table.
  - Inputs are overvoltage tolerant allowing them to go as high as 5.5 V at any valid V<sub>CC</sub>
- 2. Recommend Output Conditions:
  - Load currents should not exceed 50 mA per output and 100 mA total for the part.
  - Series resistors on the output may be used if the user desires to slow the output edge signal or limit the

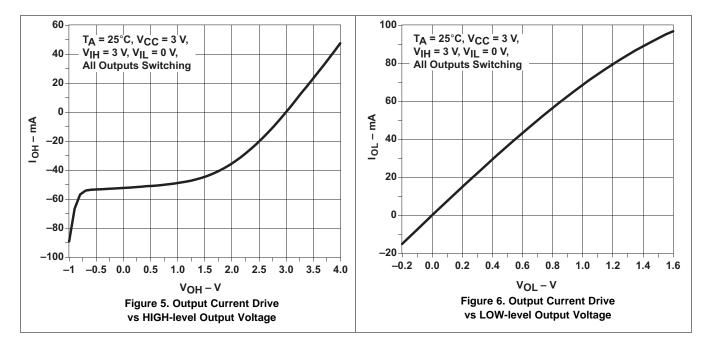
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#### **Typical Power Button Circuit (continued)**

output current.

#### 10.2.3 Application Curves



## 11 Power Supply Recommendations

The power supply can be any voltage between the minimum and maximum supply voltage rating located in the Recommended Operating Conditions table. Each  $V_{CC}$  terminal should have a good bypass capacitor to prevent power disturbance. For devices with a single supply, a 0.1- $\mu$ F capacitor is recommended and if there are multiple  $V_{CC}$  terminals then .01- $\mu$ F or .022- $\mu$ F capacitors are recommended for each power terminal. It is acceptable to parallel multiple bypass caps to reject different frequencies of noise. The 0.1- $\mu$ F and 1- $\mu$ F capacitors are commonly used in parallel. The bypass capacitor should be installed as close to the power terminal as possible for best results.



## 12 Layout

#### 12.1 Layout Guidelines

When using multiple bit logic devices, inputs should not float. In many cases, functions or parts of functions of digital logic devices are unused. Some examples are when only two inputs of a triple-input AND gate are used, or when only 3 of the 4-buffer gates are used. Such input pins should not be left unconnected because the undefined voltages at the outside connections result in undefined operational states.

Specified in Figure 7 are rules that must be observed under all circumstances. All unused inputs of digital logic devices must be connected to a high or low bias to prevent them from floating. The logic level that should be applied to any particular unused input depends on the function of the device. Generally they will be tied to GND or  $V_{CC}$ , whichever makes more sense or is more convenient. It is acceptable to float outputs unless the part is a transceiver. If the transceiver has an output enable pin, it will disable the outputs section of the part when asserted. This will not disable the input section of the I/Os so they also cannot float when disabled.

#### 12.2 Layout Example

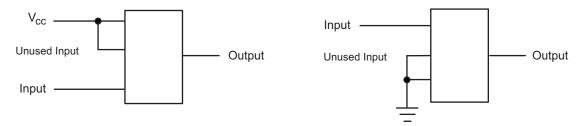


Figure 7. Layout Diagram

## 13 Device and Documentation Support

#### 13.1 Trademarks

NanoFree is a trademark of Texas Instruments.

All other trademarks are the property of their respective owners.

#### 13.2 Electrostatic Discharge Caution



This integrated circuit can be damaged by ESD. Texas Instruments recommends that all integrated circuits be handled with appropriate precautions. Failure to observe proper handling and installation procedures can cause damage.

ESD damage can range from subtle performance degradation to complete device failure. Precision integrated circuits may be more susceptible to damage because very small parametric changes could cause the device not to meet its published specifications.

#### 13.3 Glossary

SLYZ022 — TI Glossary.

This glossary lists and explains terms, acronyms and definitions.

#### 14 Mechanical, Packaging, and Orderable Information

The following pages include mechanical packaging and orderable information. This information is the most current data available for the designated devices. This data is subject to change without notice and revision of this document. For browser based versions of this data sheet, refer to the left hand navigation.





17-Aug-2015

#### PACKAGING INFORMATION

Orderable Device	Status	Package Type	Package Drawing	Pins	Package Qty	Eco Plan	Lead/Ball Finish	MSL Peak Temp	Op Temp (°C)	Device Marking (4/5)	Samples
SN74LVC2G74DCTR	ACTIVE	SM8	DCT	8	3000	Green (RoHS & no Sb/Br)	CU NIPDAU	Level-1-260C-UNLIM	-40 to 125	C74 Z	Samples
SN74LVC2G74DCTRE4	ACTIVE	SM8	DCT	8	3000	Green (RoHS & no Sb/Br)	CU NIPDAU	Level-1-260C-UNLIM	-40 to 125	C74 Z	Samples
SN74LVC2G74DCTRG4	ACTIVE	SM8	DCT	8	3000	Green (RoHS & no Sb/Br)	CU NIPDAU	Level-1-260C-UNLIM	-40 to 125	C74 Z	Samples
SN74LVC2G74DCUR	ACTIVE	VSSOP	DCU	8	3000	Green (RoHS & no Sb/Br)	CU NIPDAU   CU SN	Level-1-260C-UNLIM	-40 to 125	(74 ~ C74Q ~ C74R) CZ	Samples
SN74LVC2G74DCURE4	ACTIVE	VSSOP	DCU	8	3000	Green (RoHS & no Sb/Br)	CU NIPDAU	Level-1-260C-UNLIM	-40 to 125	C74R	Samples
SN74LVC2G74DCURG4	ACTIVE	VSSOP	DCU	8	3000	Green (RoHS & no Sb/Br)	CU NIPDAU	Level-1-260C-UNLIM	-40 to 125	C74R	Samples
SN74LVC2G74DCUT	ACTIVE	VSSOP	DCU	8	250	Green (RoHS & no Sb/Br)	CU NIPDAU   CU SN	Level-1-260C-UNLIM	-40 to 125	(C74Q ~ C74R)	Samples
SN74LVC2G74DCUTE4	ACTIVE	VSSOP	DCU	8	250	Green (RoHS & no Sb/Br)	CU NIPDAU	Level-1-260C-UNLIM	-40 to 125	C74R	Samples
SN74LVC2G74DCUTG4	ACTIVE	VSSOP	DCU	8	250	Green (RoHS & no Sb/Br)	CU NIPDAU	Level-1-260C-UNLIM	-40 to 125	C74R	Samples
SN74LVC2G74YZPR	ACTIVE	DSBGA	YZP	8	3000	Green (RoHS & no Sb/Br)	SNAGCU	Level-1-260C-UNLIM	-40 to 85	(CP7 ~ CPN)	Samples

(1) The marketing status values are defined as follows:

**ACTIVE:** Product device recommended for new designs.

LIFEBUY: TI has announced that the device will be discontinued, and a lifetime-buy period is in effect.

NRND: Not recommended for new designs. Device is in production to support existing customers, but TI does not recommend using this part in a new design.

PREVIEW: Device has been announced but is not in production. Samples may or may not be available.

**OBSOLETE:** TI has discontinued the production of the device.

**TBD:** The Pb-Free/Green conversion plan has not been defined.

**Pb-Free (RoHS):** TI's terms "Lead-Free" or "Pb-Free" mean semiconductor products that are compatible with the current RoHS requirements for all 6 substances, including the requirement that lead not exceed 0.1% by weight in homogeneous materials. Where designed to be soldered at high temperatures, TI Pb-Free products are suitable for use in specified lead-free processes.

**Pb-Free (RoHS Exempt):** This component has a RoHS exemption for either 1) lead-based flip-chip solder bumps used between the die and package, or 2) lead-based die adhesive used between the die and leadframe. The component is otherwise considered Pb-Free (RoHS compatible) as defined above.

Green (RoHS & no Sb/Br): TI defines "Green" to mean Pb-Free (RoHS compatible), and free of Bromine (Br) and Antimony (Sb) based flame retardants (Br or Sb do not exceed 0.1% by weight in homogeneous material)

<sup>(2)</sup> Eco Plan - The planned eco-friendly classification: Pb-Free (RoHS), Pb-Free (RoHS Exempt), or Green (RoHS & no Sb/Br) - please check http://www.ti.com/productcontent for the latest availability information and additional product content details.





17-Aug-2015

- (3) MSL, Peak Temp. The Moisture Sensitivity Level rating according to the JEDEC industry standard classifications, and peak solder temperature.
- (4) There may be additional marking, which relates to the logo, the lot trace code information, or the environmental category on the device.
- (5) Multiple Device Markings will be inside parentheses. Only one Device Marking contained in parentheses and separated by a "~" will appear on a device. If a line is indented then it is a continuation of the previous line and the two combined represent the entire Device Marking for that device.
- (6) Lead/Ball Finish Orderable Devices may have multiple material finish options. Finish options are separated by a vertical ruled line. Lead/Ball Finish values may wrap to two lines if the finish value exceeds the maximum column width.

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#### OTHER QUALIFIED VERSIONS OF SN74LVC2G74:

Automotive: SN74LVC2G74-Q1

Enhanced Product: SN74LVC2G74-EP

NOTE: Qualified Version Definitions:

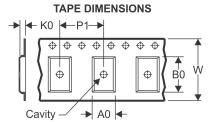
- Automotive Q100 devices qualified for high-reliability automotive applications targeting zero defects
- Enhanced Product Supports Defense, Aerospace and Medical Applications

## PACKAGE MATERIALS INFORMATION

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## TAPE AND REEL INFORMATION





Α0	Dimension designed to accommodate the component width
B0	Dimension designed to accommodate the component length
	Dimension designed to accommodate the component thickness
W	Overall width of the carrier tape
P1	Pitch between successive cavity centers

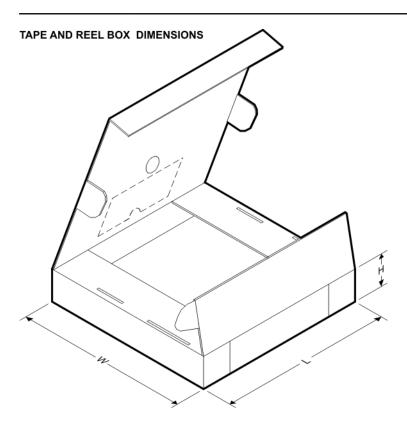
#### QUADRANT ASSIGNMENTS FOR PIN 1 ORIENTATION IN TAPE



#### \*All dimensions are nominal

All diffiersions are nominal												
Device	Package Type	Package Drawing		SPQ	Reel Diameter (mm)	Reel Width W1 (mm)	A0 (mm)	B0 (mm)	K0 (mm)	P1 (mm)	W (mm)	Pin1 Quadrant
SN74LVC2G74DCUR	VSSOP	DCU	8	3000	180.0	8.4	2.25	3.35	1.05	4.0	8.0	Q3
SN74LVC2G74DCURG4	VSSOP	DCU	8	3000	180.0	8.4	2.25	3.35	1.05	4.0	8.0	Q3
SN74LVC2G74DCUTG4	VSSOP	DCU	8	250	180.0	8.4	2.25	3.35	1.05	4.0	8.0	Q3
SN74LVC2G74YZPR	DSBGA	YZP	8	3000	178.0	9.2	1.02	2.02	0.63	4.0	8.0	Q1

www.ti.com 19-Aug-2015

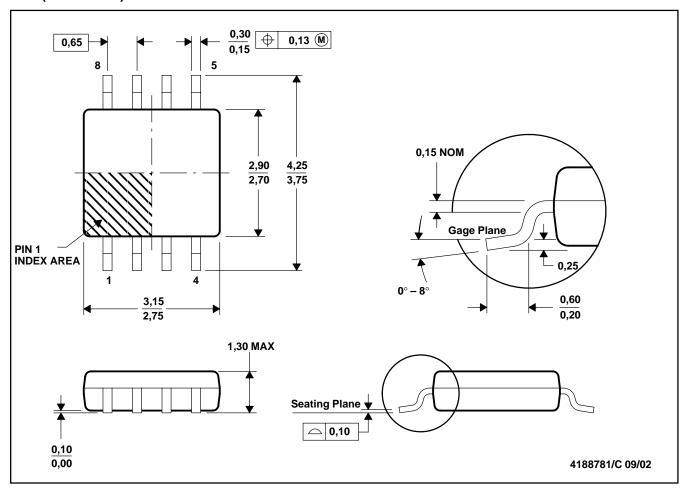


\*All dimensions are nominal

Device	Package Type	Package Drawing	Pins	SPQ	Length (mm)	Width (mm)	Height (mm)
SN74LVC2G74DCUR	VSSOP	DCU	8	3000	202.0	201.0	28.0
SN74LVC2G74DCURG4	VSSOP	DCU	8	3000	202.0	201.0	28.0
SN74LVC2G74DCUTG4	VSSOP	DCU	8	250	202.0	201.0	28.0
SN74LVC2G74YZPR	DSBGA	YZP	8	3000	220.0	220.0	35.0

## DCT (R-PDSO-G8)

#### PLASTIC SMALL-OUTLINE PACKAGE

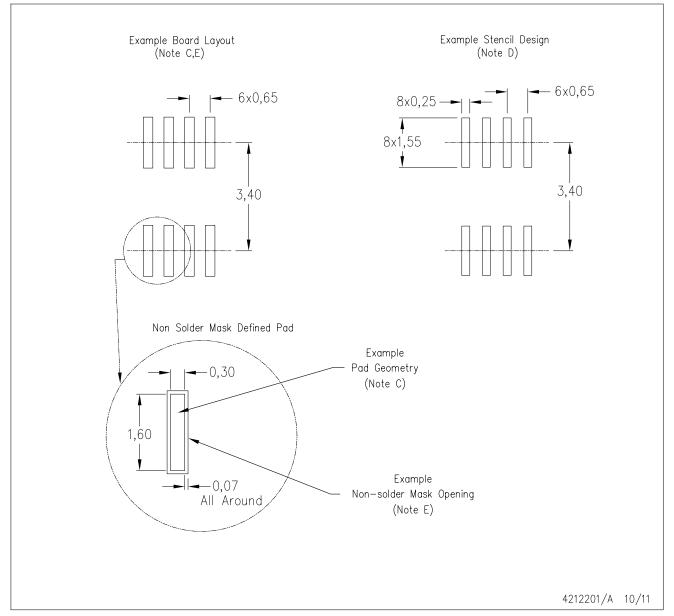


NOTES: A. All linear dimensions are in millimeters.

- B. This drawing is subject to change without notice.
- C. Body dimensions do not include mold flash or protrusion
- D. Falls within JEDEC MO-187 variation DA.

# DCT (R-PDSO-G8)

## PLASTIC SMALL OUTLINE



NOTES: A. All linear dimensions are in millimeters.

- B. This drawing is subject to change without notice.
- C. Publication IPC-7351 is recommended for alternate designs.
- D. Laser cutting apertures with trapezoidal walls and also rounding corners will offer better paste release. Customers should contact their board assembly site for stencil design recommendations. Refer to IPC-7525.
- E. Customers should contact their board fabrication site for solder mask tolerances between and around signal pads.



# DCU (R-PDSO-G8)

# PLASTIC SMALL-OUTLINE PACKAGE (DIE DOWN)



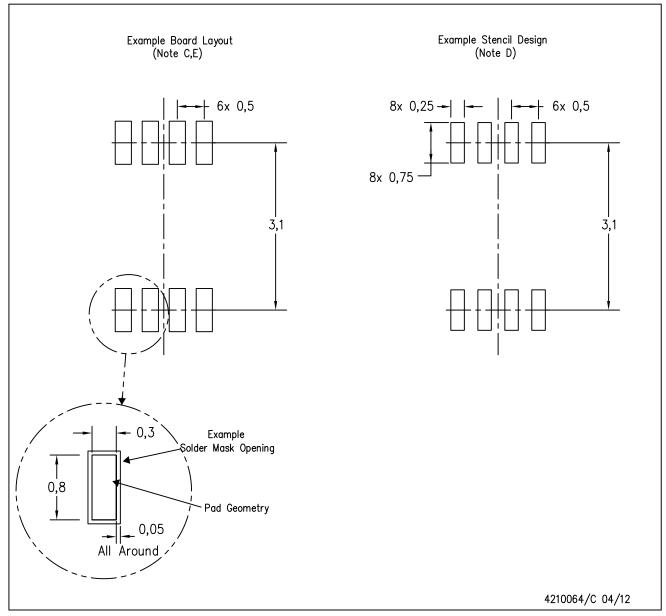
NOTES:

- : A. All linear dimensions are in millimeters.
  - B. This drawing is subject to change without notice.
  - C. Body dimensions do not include mold flash or protrusion. Mold flash and protrusion shall not exceed 0.15 per side.
  - D. Falls within JEDEC MO-187 variation CA.



DCU (S-PDSO-G8)

PLASTIC SMALL OUTLINE PACKAGE (DIE DOWN)



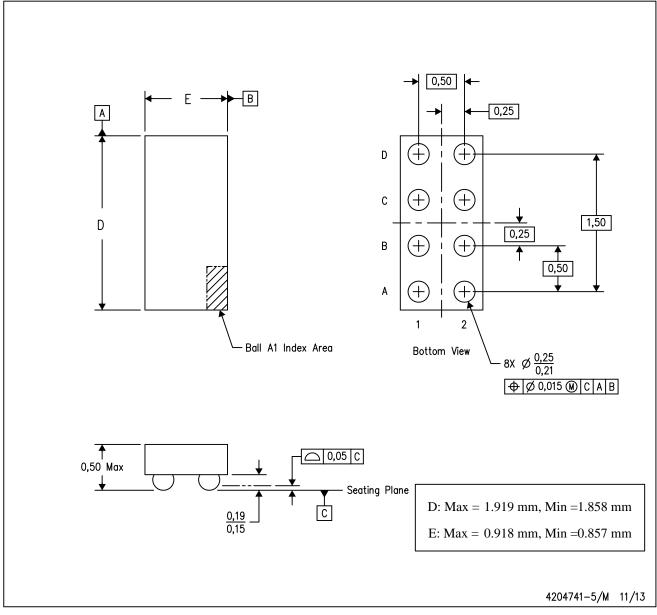
NOTES: A. All linear dimensions are in millimeters.

- B. This drawing is subject to change without notice.
- C. Publication IPC-7351 is recommended for alternate designs.
- D. Laser cutting apertures with trapezoidal walls and also rounding corners will offer better paste release. Customers should contact their board assembly site for stencil design recommendations. Refer to IPC-7525 for other stencil recommendations.
- E. Customers should contact their board fabrication site for solder mask tolerances between and around signal pads.



YZP (R-XBGA-N8)

DIE-SIZE BALL GRID ARRAY



NOTES: A. All linear dimensions are in millimeters. Dimensioning and tolerancing per ASME Y14.5M-1994.

- B. This drawing is subject to change without notice.
- C. NanoFree™ package configuration.

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